

Supplementary Materials for
**Visible and infrared dual-band imaging via Ge/MoS₂ van der
Waals heterostructure**

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Supplementary Text

Figs. S1 to S18

Table S1

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Supplementary Text

Density Functional Theory (DFT) Simulation

Band structures, local density of states (LDOS) and geometry optimization calculations are performed with DFT implemented in QuantumATK software (Synopsys) (30, 31). We employ generalized gradient approximation (GGA) and SG15 pseudopotentials to represent exchange–correlation potentials and pseudopotentials, respectively. For Ge, pseudopotential projector shift (pps) is adopted to predict the correct band gap. First, we calculate the band structures of bulk Ge and bulk MoS₂ to ensure that the calculations reproduce the experimentally measured band gap well. A k-point mesh of 9×9×9 and a mesh cut-off energy of 100 Hartree are used for bulk Ge while a k-point mesh of 10×10×3 and a mesh cut-off energy of 75 Hartree for bulk MoS₂. Geometry optimizations are performed until the residual force on each atom becomes less than 0.05 eV Å⁻¹. As shown from the band structures of bulk Ge and bulk MoS₂ in Figure S18, calculated band gap sizes of bulk Ge and bulk MoS₂ are close to the experimentally reported values. For the LDOS calculation, Ge/MoS₂ heterostructure is constructed by putting MoS₂ on top of the Ge (100) surface as shown in Figure S9. Unsaturated Ge adatom on the (100) surface are passivated by the hydrogen adatom to prevent the effect of dangling bonds. Semi-infinite Ge and MoS₂ are assumed on the left and right sides of the structure, respectively. In LDOS plots, brighter color corresponds to higher LDOS values. Therefore, we can estimate the CB and VB edges of Ge and MoS₂ at each location of the Ge/MoS₂ heterostructure.

Evidence of Trap-assisted Tunneling Current at Photoconductive Mode

We measured the band alignment based on our experimental XPS, UPS, and EELS results showing the type-II band alignment with accumulation at the heterojunction interface (see Fig. 1F) (32–36). Generally, the 2D MoS₂ allows for such type-II configuration (8), but since the electron affinity of MoS₂ is larger than that of Ge, our proposed MoS₂/Ge heterojunction exhibits the accumulated type-II at the MoS₂ interface. The band structure is the general bending configuration in other similar work function combinations. Based on the type-II structure, the n-type MoS₂ to be more n⁺-doped at the interface. To clarify the difference between the n-doped (unintentionally doped) and n⁺-doped MoS₂ heterojunctions, we added case-by-case band alignments and FN plots. Figure S6A shows the type-II heterojunction for both n-doped and n⁺-doped MoS₂ structures. The shown band alignment as based on our experimentally measured XPS, UPS, and EELS results. The n⁺-doping distribution leads to less bending of the MoS₂ side and allows the expansion of the depletion region more toward to the Ge side. This directional expansion is more obvious under reverse bias; the n⁺-doped MoS₂ heterojunction allows the Ge region to be bent further. As a result, the thicker tunneling barrier is formed, reducing the tunneling effect. The lower dark current is thus attributed only to the diffusion current from thermally generated carriers, similarly to normal pn diodes. In contrast, the tunneling barrier of the n-doped MoS₂ heterostructure exhibits a thin triangle shape (due to the expanded depletion region), and this additional tunneling current (as a FN tunneling mechanism) contributes to the high dark current.

According to the ref. (37), the direct and FN tunneling currents can be expressed by

$$I_{Direct} \propto V \exp\left(-\frac{4\pi d \sqrt{2m^* \phi}}{h}\right)$$

$$I_{FN} \propto V^2 \exp\left(-\frac{8\pi d \sqrt{2m^* \phi^3}}{3\hbar e V}\right)$$

where d , m^* , ϕ , $\hbar$ are the tunneling thickness, effective electron mass, tunneling barrier, and the Plank constant. To identify which tunneling current type is incorporated in our MoS₂/Ge heterojunction, $\ln(I/V^2)$ vs $1/V$ (FN plot) curve is plotted based on the experimental and I - V data.

As shown in Fig. S6B, when $1/V < 1$, the n-doped MoS₂/Ge structure exhibits a linear-decrease curve, increasing the FN tunneling effect in this region (37). On the other hand, the n⁺-doped MoS₂/Ge structure exhibits a quasi-linear-increase curve, which is not attributed to the FN tunneling effect. Although the increasing linear curve might be due to the direct tunneling, as shown in Fig. S6C, the linear curve implies that the current mechanism is not based on the direct tunneling (since $\ln(I/V)$ should be constant in this plot according to the I_{Direct} equation above), but based on the thermally generated carriers. Therefore, based on these results, our MoS₂/Ge heterojunction allows for the selective VIS detection (not detecting infrared) capability at the photoconductive mode via the high tunneling current.

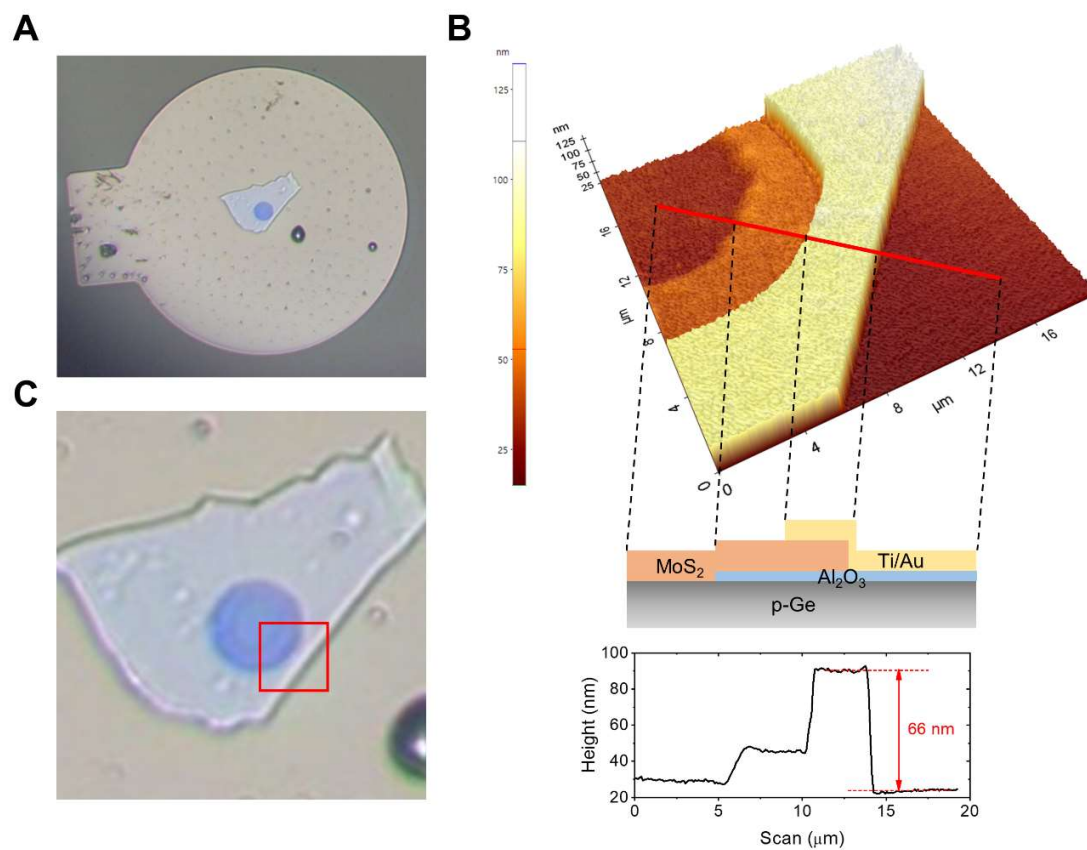


Fig. S1. Device height analysis. (A) Optical microscopy of the device. Scale-bar: 300 μm . (B) Atomic force microscopy map of the device with the corresponding cross-sectional device structure targeting on the (C) red box.

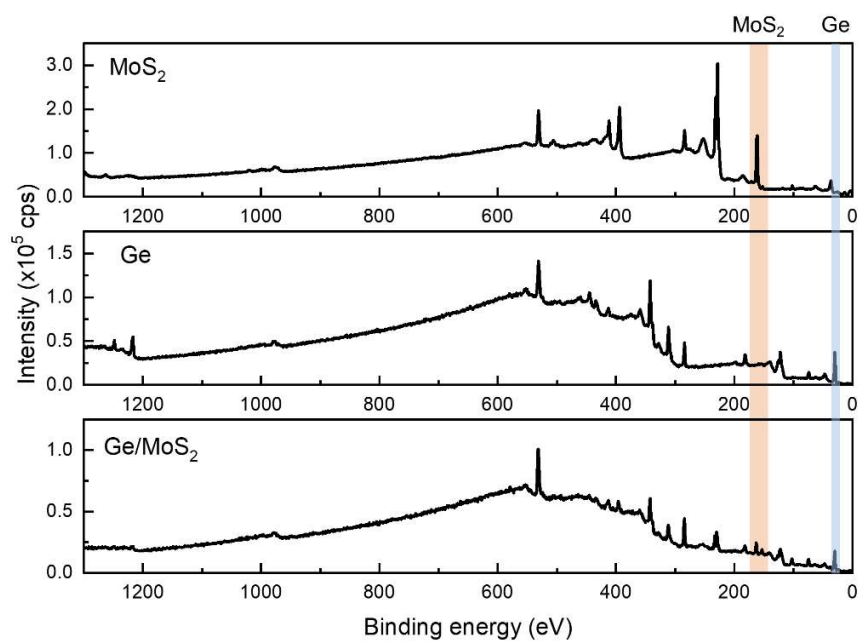


Fig. S2. X-ray photoelectron spectroscopy (XPS) survey spectra.

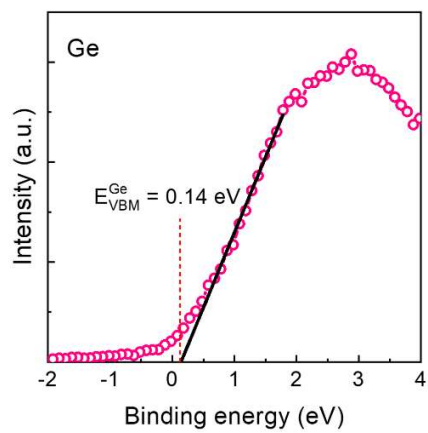
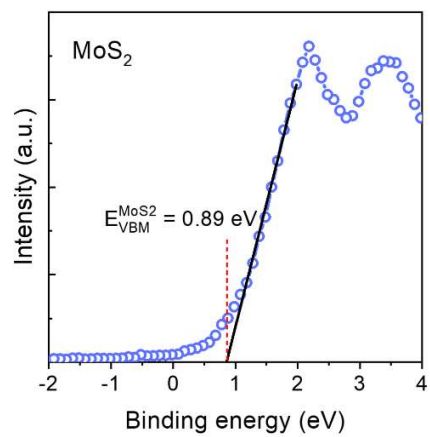
A**B**

Fig. S3. Ultraviolet photoelectron spectroscopy (UPS) results. (A) Ge and (B) MoS₂.

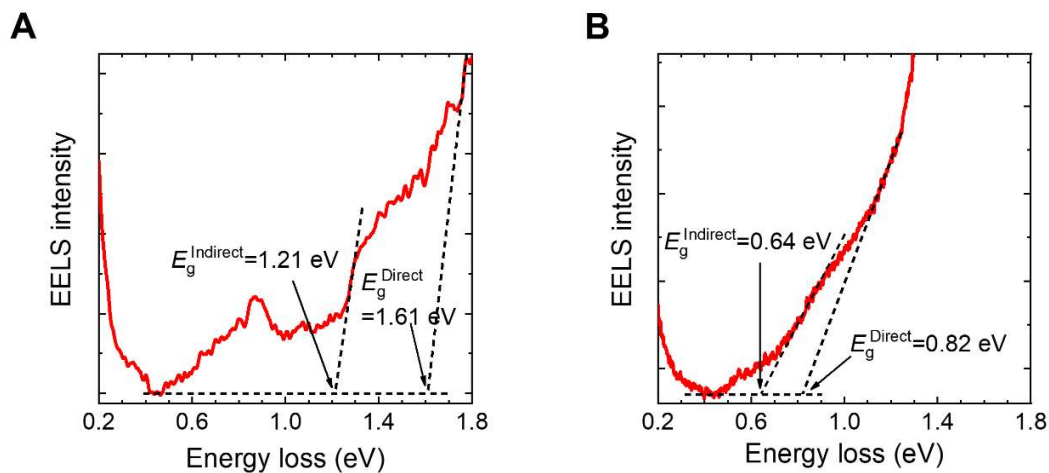


Fig. S4. Electron energy loss spectroscopy (EELS) results of MoS₂ and Ge. (A) EELS result of bulk MoS₂ and (B) EELS result of Ge. The corresponding indirect and direct bandgaps are 1.21 eV and 1.61 eV for Ge, respectively, and 0.64 eV and 0.82 eV for MoS₂, respectively.

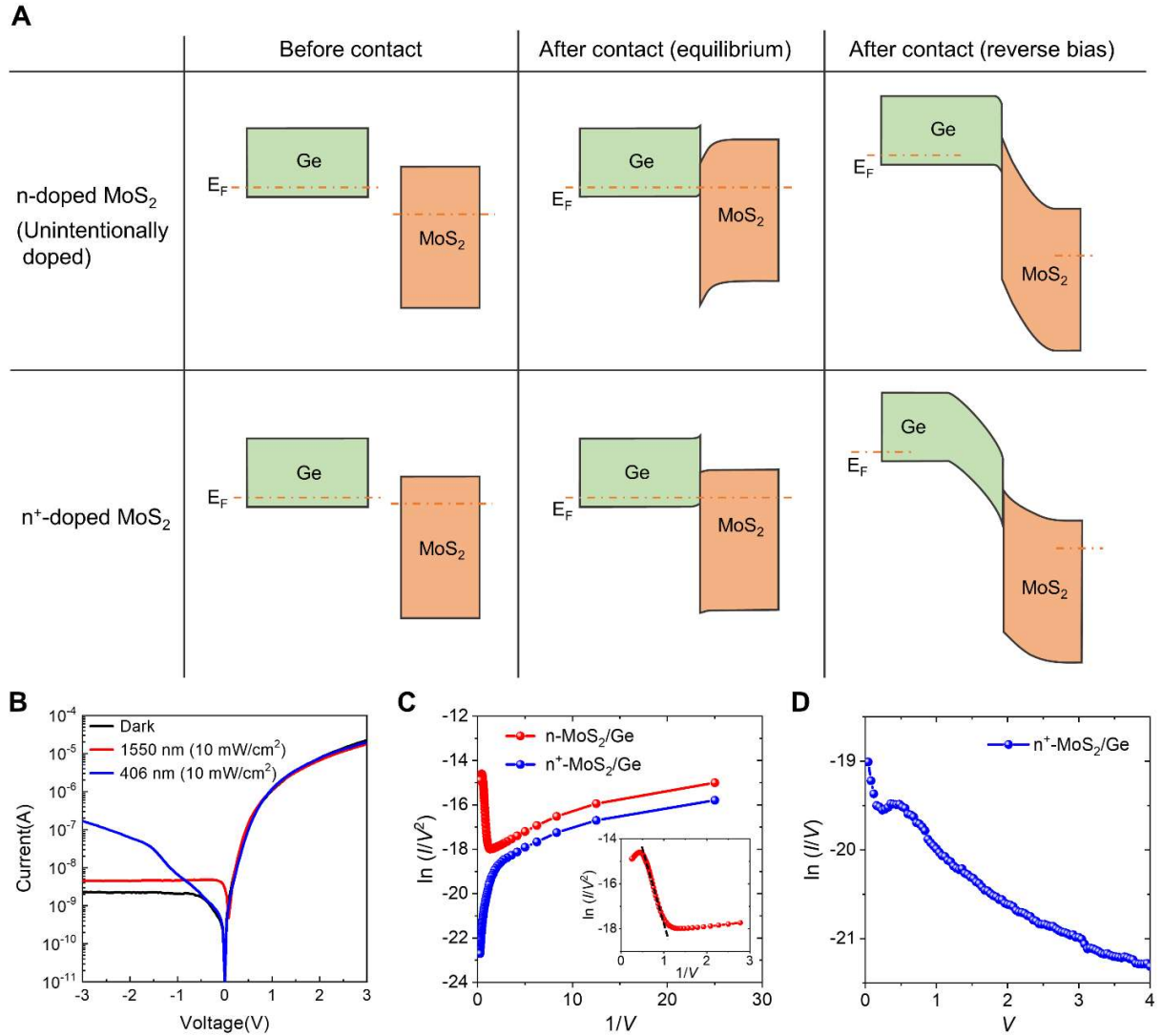


Fig. S5. Current characteristic comparison to n-doped (unintentionally doped)/n⁺-doped MoS₂/Ge heterostructure. (A) Schematic band alignments for n-doped/n⁺-doped MoS₂ at various states. **(B)** Current-voltage (I - V) characteristics of the Ge/n⁺-MoS₂ photodetector in dark and at 466 and 1550 nm. The shift is due to the diffusion/drift transport of the photogenerated electrons and holes swept out from the depletion region, which is a general mechanism in photodetectors and solar cells. **(C)** Fowler-Nordheim (FN) plots. **(D)** $\ln(I/V)$ vs V plots.

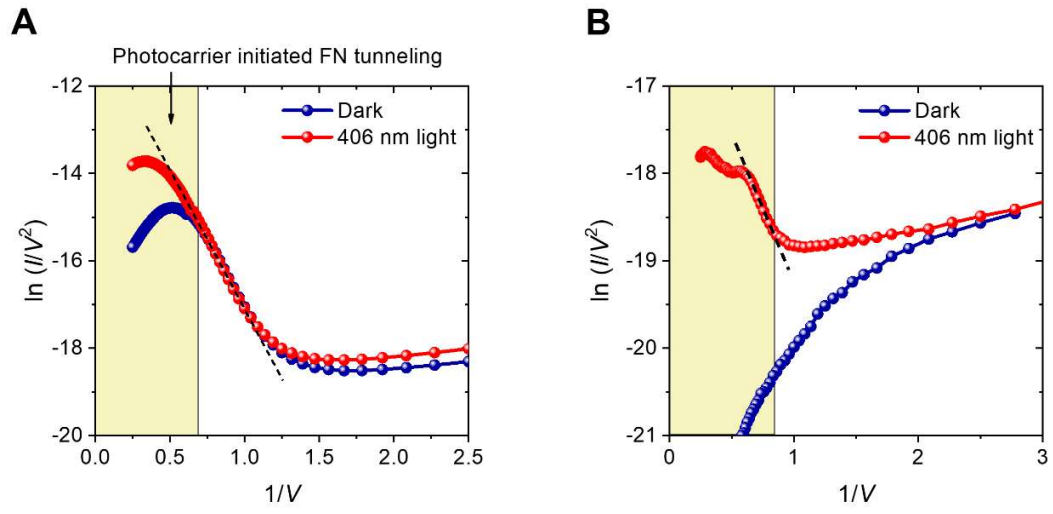


Fig. S6. Light/dark Fowler-Nordheim (FN) plots. FN plots for (A) n-doped (unintentionally doped) and (B) n⁺-doped MoS₂/Ge heterojunction photodiodes.

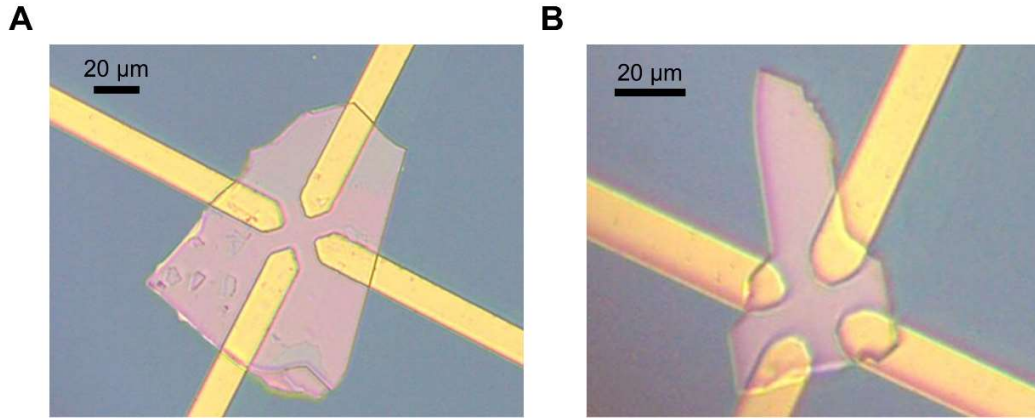


Fig. S7. Optical microscopy image of MoS₂. (A) n-doped (unintentionally doped) MoS₂. The measured surface carrier concentration (n_s), mobility, and doping concentration are $5.337 \times 10^9 \text{ cm}^{-2}$, $188 \text{ cm}^2/\text{V}\cdot\text{s}$, and $7.624 \times 10^{14} \text{ cm}^{-3}$, respectively. (B) n⁺-doped MoS₂. The measured n_s , mobility, and doping concentration are $3.869 \times 10^9 \text{ cm}^{-2}$, $23.69 \text{ cm}^2/\text{V}\cdot\text{s}$, and $5.528 \times 10^{17} \text{ cm}^{-3}$, respectively.

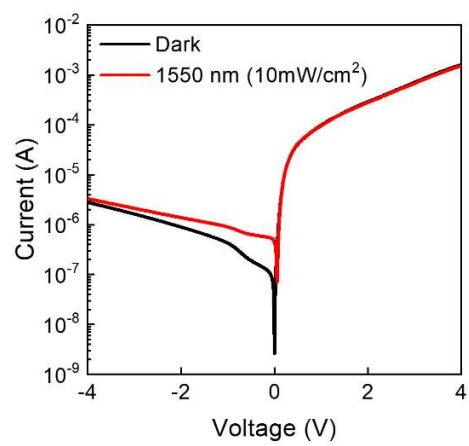


Fig. S8. Current-voltage (I - V) characteristics of pn-Ge.

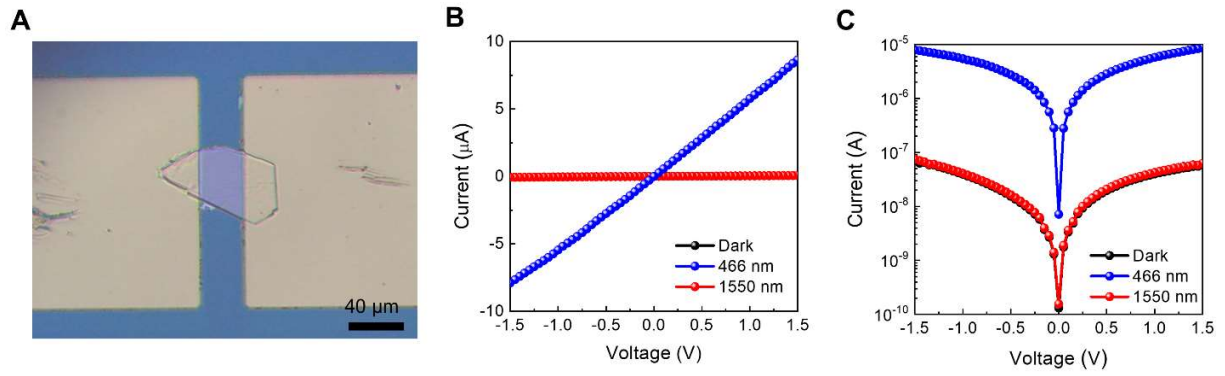


Fig. S9. MoS₂/Ti/Au Schottky diode. (A) Optical microscopy image of the diode including a MoS₂ flake. Current-voltage (I - V) characteristics of the diode under dark, 466 nm, and 1550 nm conditions in (B) linear scale and (C) logarithmic scale. The light intensity is 30 mW/cm².

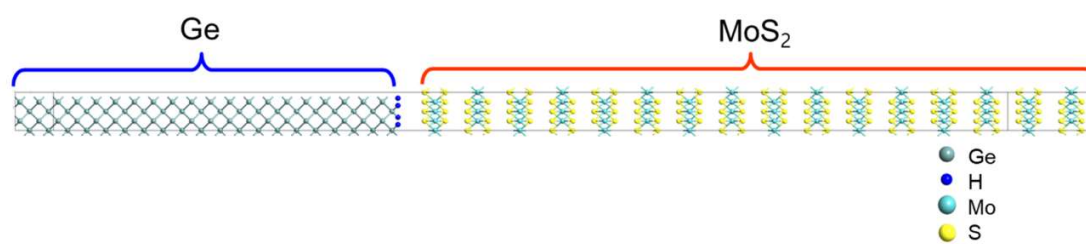


Fig. S10. Simulated Ge/MoS₂ heterostructure.

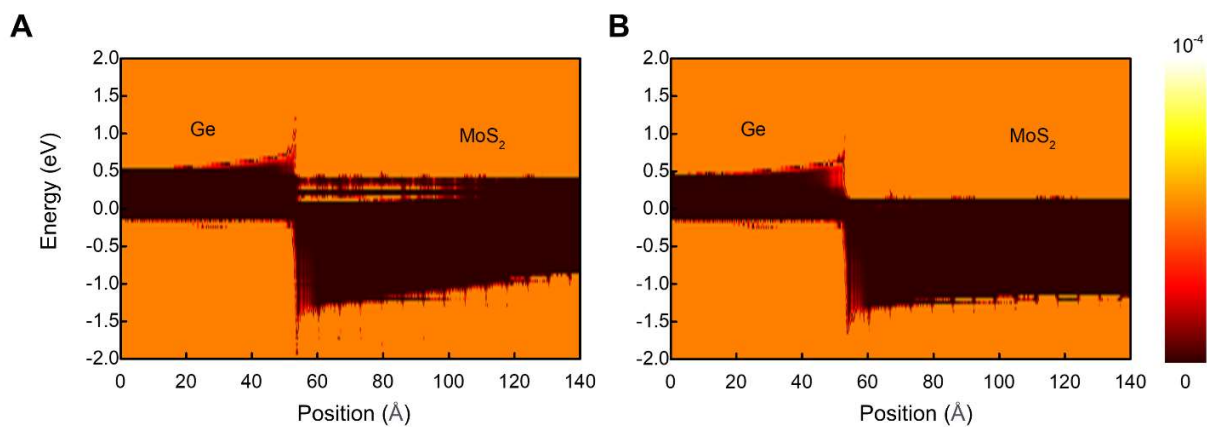


Fig. S11. Density functional theory (DFT) simulations. (A) Ge/MoS₂ heterostructure. (B) Heterostructure of Ge and n⁺-doped MoS₂. Color map: local density of states [$\text{\AA}^{-3} \cdot \text{eV}^{-1}$].

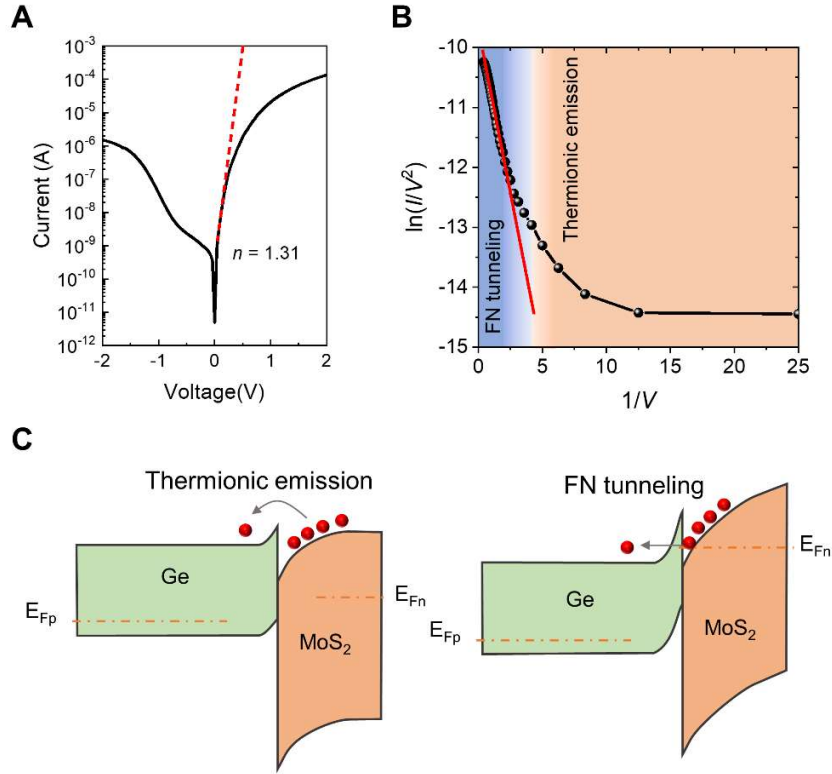


Fig. S12. Current transport characteristics. (A) Current-voltage (I - V) characteristic with ideality factors under dark condition. (B) Fowler-Nordheim (FN) plots. At $0 < 1/V < 2.27$ V, the plot shows a linear curve, implying the FN tunneling dominance in this voltage region. (C) Schematic band diagrams. At small forward bias, a thermionic emission of electrons in the MoS₂ over the conduction band offset mostly contribute to a forward current. As a forward bias increases, the barrier becomes a thinner, allowing the FN tunneling of electrons.

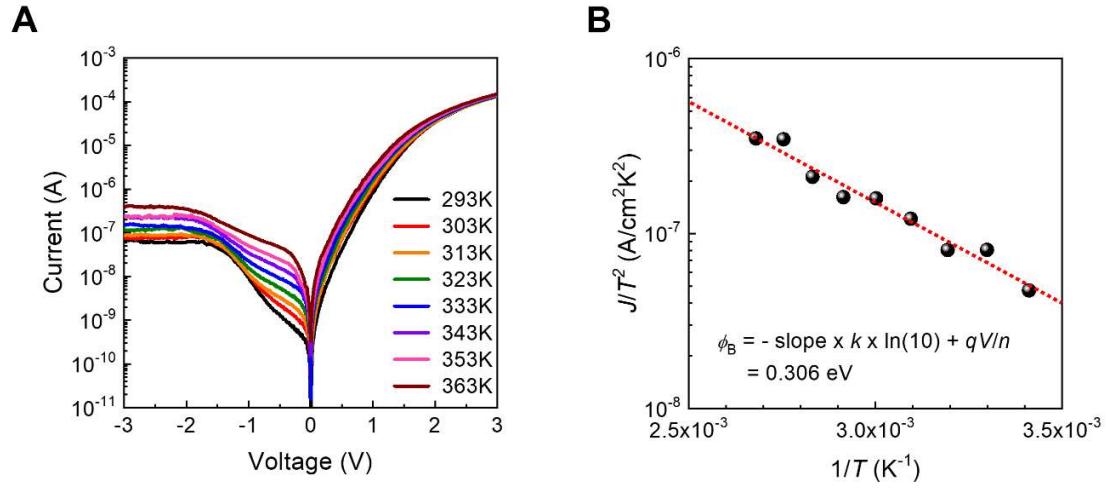


Fig. S13. Temperature-dependent current transport characteristics. (A) Temperature-dependent current-voltage (I - V) characteristics. (B) $\log(J/T^2)$ vs $1/T$ plot under forward bias. $V=0.1$ V and $n=1.31$ are used to calculate the barrier.

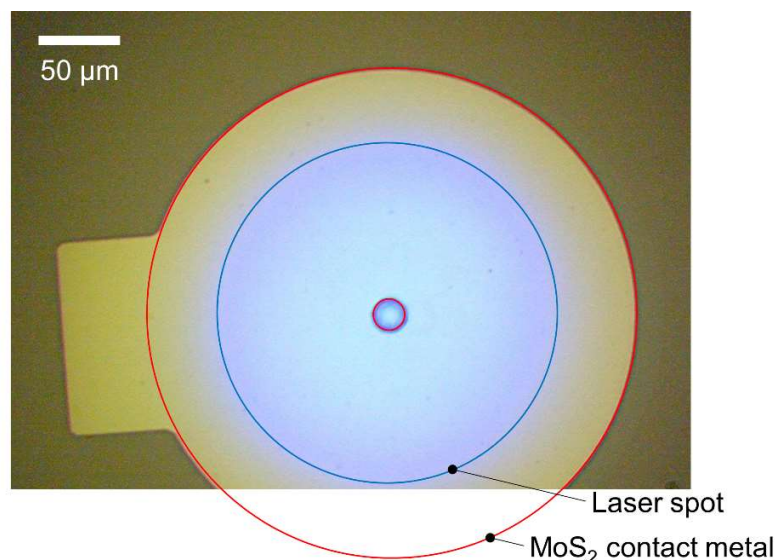


Fig. S14. Laser spot size compared to the MoS₂ contact metal.

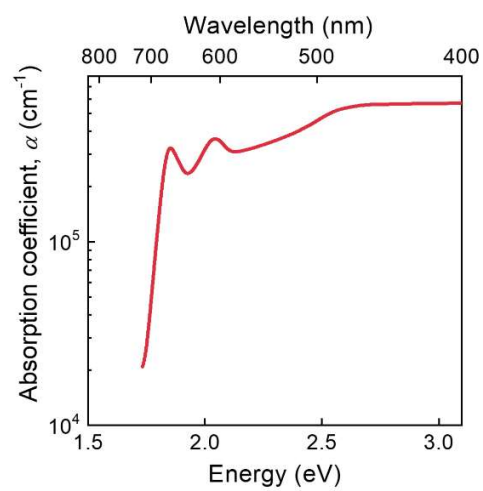


Fig. S15. Measured absorption spectrum of 69-nm MoS₂ flake.

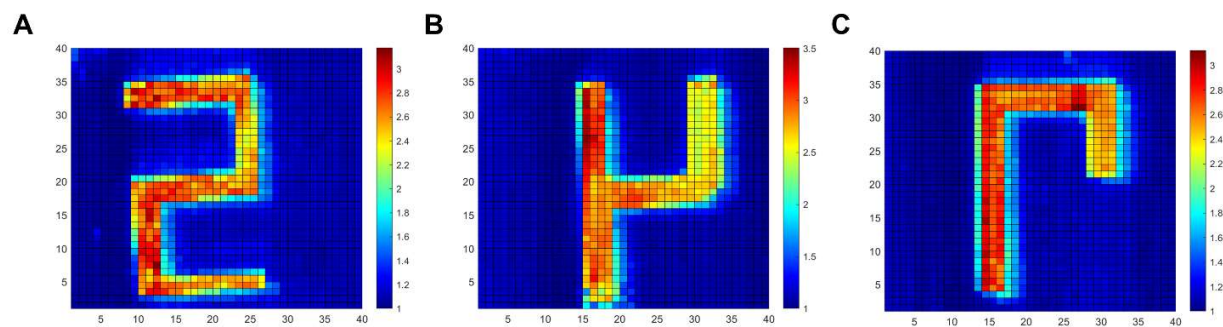


Fig. S16. Infrared imaging capability of the MoS₂/Ge heterostructure. Various geometries are imaged, such as (A) “2,” (B) “4,” and (C) “7.”

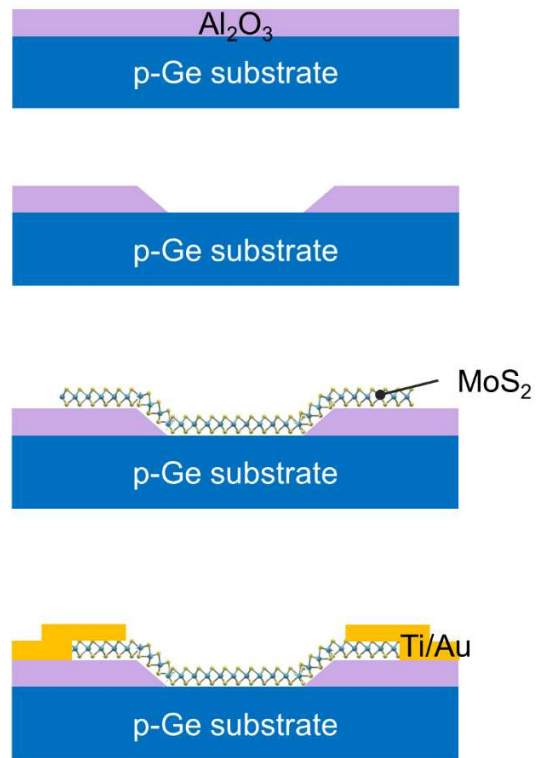


Fig. S17. Schematic of the fabrication of the p-Ge/MoS₂ quasi van der Waals heterojunction photodetector.

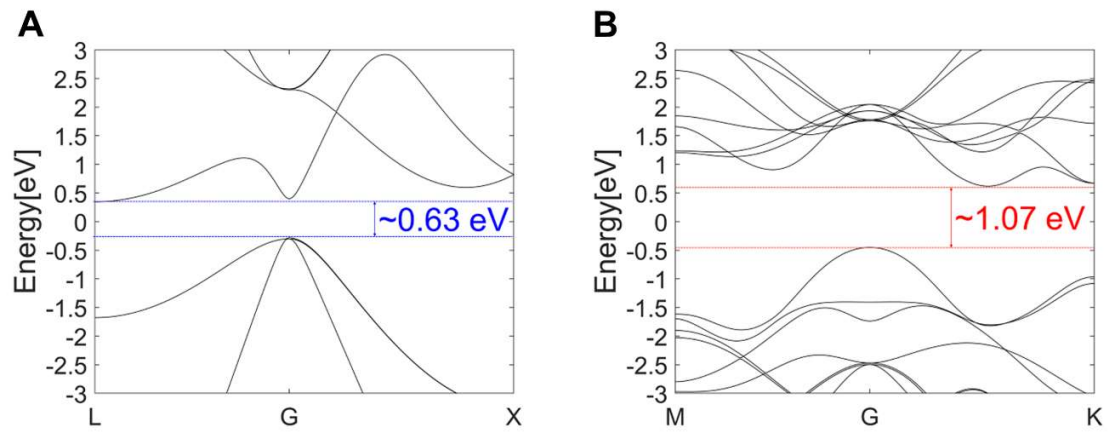


Fig. S18. Band structures of materials in the heterostructure. Band structure of (A) bulk Ge and (B) bulk MoS₂.

Dual-band (ref)	Structure	Materials	Responsivity (AW^{-1})	Applications	Year
NIR/VIS (This work)	Heterojunction	p-Ge/MoS ₂	<2.5	Selective imaging	-
SWIR/MWIR (12)	Back-to-back	CQDs	<10 ⁻²	Imaging, temperature recognition	2019
NIR/VIS (14)	Heterojunction	Organics	>10 ²	-	2020
NIR/VIS (15)	Back-to-back	pn-Ge/pn-Si	<0.6	-	2019
UV/MIR (38)	Back-to-back (3-terminal)	ZnO-NN/ G/InAs-NN	<15	-	2021
UV-VIS-NIR (39)	Heterojunction	Perovskite/Si	<0.05	-	2020

Table. S1. Comparison of recent multi-band photodetectors.

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